



# STGD10HF60KD

10 A, 600 V, short-circuit rugged IGBT  
with Ultrafast diode

Preliminary data

## Features

- Low on-voltage drop ( $V_{CE(sat)}$ )
- Low  $C_{res} / C_{ies}$  ratio (no cross conduction susceptibility)
- Switching losses include diode recovery energy
- Short-circuit rated
- Very soft Ultrafast recovery anti-parallel diode

## Applications

- High frequency inverters
- SMPS and PFC in both hard switch and resonant topologies
- Motor drives
- Injection systems

## Description

This device utilizes the advanced PowerMESH™ process for the IGBT and the Turbo 2 Ultrafast high voltage technology for the diode. The combination results in a very good trade-off between conduction losses and switching behavior rendering the product ideal for diverse high voltage applications operating at high frequencies.

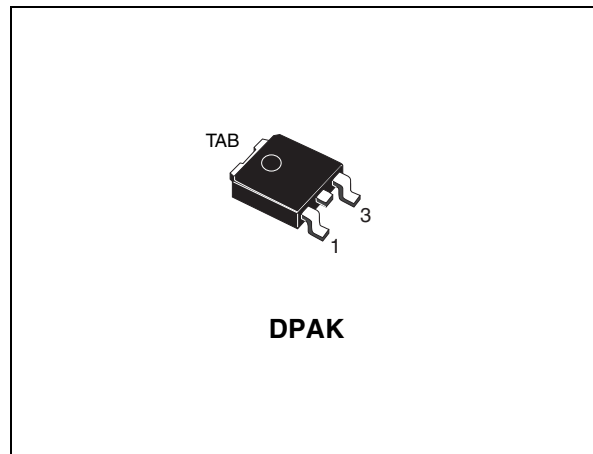


Figure 1. Internal schematic diagram

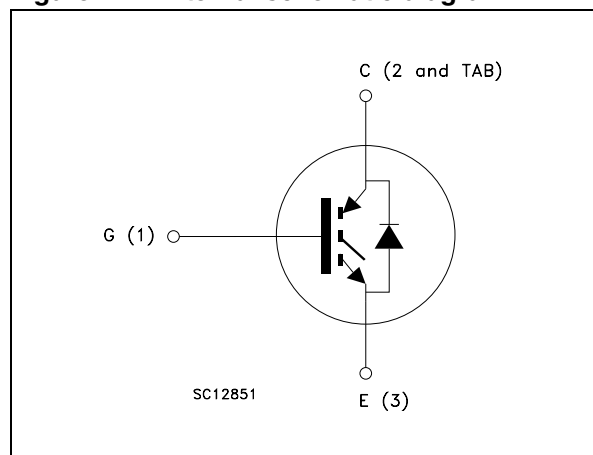


Table 1. Device summary

Order code	$V_{CES}$	Package	Packaging
STGD10HF60KD	600 V	DPAK	Tape and reel

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# 1 Electrical ratings

$T_{CASE} = 25\text{ °C}$  unless otherwise specified.

**Table 2. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{CES}$	Collector-emitter voltage ( $V_{GE} = 0$ )	600	V
$I_C^{(1)}$	Collector current (continuous) at $T_C = 25\text{ °C}$	18	A
$I_C^{(1)}$	Collector current (continuous) at $T_C = 100\text{ °C}$	10	A
$I_{CL}^{(2)}$	Turn-off latching current	30	A
$I_{CP}^{(3)}$	Pulsed collector current	30	A
$V_{GE}$	Gate-emitter voltage	$\pm 20$	V
$V_{GEM}$	Gate-emitter voltage pulsed ( $t_p \leq 1\text{ ms}$ )	$\pm 30$	V
$I_F$	Diode RMS forward current	7	A
$I_{FSM}$	Surge non repetitive forward current $t_p = 10\text{ ms}$ sinusoidal	20	A
$P_{TOT}$	Total dissipation	62.5	W
$t_{scw}$	Short circuit withstand time ( $V_{CE} = 50\text{ V}$ , $V_{GE} = 15\text{ V}$ , $T_C = 150\text{ °C}$ )	10	$\mu\text{s}$
$T_j$	IGBT operating junction temperature	- 55 to 150	$^{\circ}\text{C}$
	Diode operating junction temperature	- 55 to 175	$^{\circ}\text{C}$
$T_{stg}$	Storage temperature	- 65 to 150	$^{\circ}\text{C}$

1. Calculated according to the iterative formula:

$$I_C(T_C) = \frac{T_{j(max)} - T_C}{R_{thj-c} \times V_{CE(sat)(max)}(T_{j(max)}, I_C(T_C))}$$

2.  $V_{clamp} = 80\%$  of  $V_{CES}$ ,  $T_j = 150\text{ °C}$ ,  $R_G = 10\ \Omega$ ,  $V_{GE} = 15\text{ V}$

3. Pulse width limited by max. junction temperature allowed

**Table 3. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case IGBT	2	$^{\circ}\text{C/W}$
$R_{thj-case}$	Thermal resistance junction-case diode	5.8	$^{\circ}\text{C/W}$
$R_{thj-amb}$	Thermal resistance junction-ambient	100	$^{\circ}\text{C/W}$

## 2 Electrical characteristics

$T_{CASE}=25\text{ °C}$  unless otherwise specified.

**Table 4. Static**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)CES}$	Collector-emitter breakdown voltage ( $V_{GE}=0$ )	$I_C = 1\text{ mA}$ , $T_C = -40\text{ °C}$ <sup>(1)</sup>		610		V
		$I_C = 1\text{ mA}$	600	650		V
		$I_C = 1\text{ mA}$ , $T_C = 125\text{ °C}$		700		V
$I_{GES}$	Gate-emitter leakage current ( $V_{CE} = 0$ )	$V_{GE} = \pm 20\text{ V}$ $V_{GE} = \pm 20\text{ V}$ , $T_C = 125\text{ °C}$			$\pm 100$ $\pm 1$	nA $\mu\text{A}$
$I_{CES}$	Collector cut-off current ( $V_{GE} = 0$ )	$V_{CE} = 600\text{ V}$ $V_{CE} = 600\text{ V}$ , $T_C = 125\text{ °C}$			150 1	$\mu\text{A}$ mA
$V_{GE(th)}$	Gate threshold voltage	$V_{CE} = V_{GE}$ , $I_C = 250\text{ }\mu\text{A}$	4.5		6.5	V
$V_{CE(sat)}$	Collector-emitter saturation voltage	$V_{GE} = 15\text{ V}$ , $I_C = 5\text{ A}$	1.75	2.25	2.75	V

1. Limits guaranteed by design

**Table 5. Dynamic <sup>(1)</sup>**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$C_{ies}$	Input capacitance	$V_{CE} = 25\text{ V}$ , $f = 1\text{ MHz}$ , $V_{GE} = 0$		450		pF
$C_{oes}$	Output capacitance		-	55	-	pF
$C_{res}$	Reverse transfer capacitance				10	pF
$Q_g$	Total gate charge	$V_{CE} = 400\text{ V}$ , $I_C = 5\text{ A}$ , $V_{GE} = 15\text{ V}$		23		nC
$Q_{ge}$	Gate-emitter charge		-	TBD	-	nC
$Q_{gc}$	Gate-collector charge				TBD	nC

1. Limits guaranteed by design

**Table 6. Switching on/off (inductive load) <sup>(1)</sup>**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$t_{d(on)}$ $t_r$ $(di/dt)_{on}$	Turn-on delay time Current rise time Turn-on current slope	$V_{CC} = 400\text{ V}$ , $I_C = 5\text{ A}$ $R_G = 10\ \Omega$ , $V_{GE} = 15\text{ V}$	-	15 6.2 620	-	ns ns A/ $\mu$ s
$t_{d(on)}$ $t_r$ $(di/dt)_{on}$	Turn-on delay time Current rise time Turn-on current slope	$V_{CC} = 400\text{ V}$ , $I_C = 5\text{ A}$ $R_G = 10\ \Omega$ , $V_{GE} = 15\text{ V}$ $T_C = 125\text{ }^\circ\text{C}$	-	15 6.3 610	-	ns ns A/ $\mu$ s
$t_r(V_{off})$ $t_{d(off)}$ $t_f$	Off voltage rise time Turn-off delay time Current fall time	$V_{CC} = 400\text{ V}$ , $I_C = 5\text{ A}$ , $R_{GE} = 10\ \Omega$ , $V_{GE} = 15\text{ V}$	-	22 30 70	-	ns ns ns
$t_r(V_{off})$ $t_{d(off)}$ $t_f$	Off voltage rise time Turn-off delay time Current fall time	$V_{CC} = 400\text{ V}$ , $I_C = 5\text{ A}$ , $R_{GE} = 10\ \Omega$ , $V_{GE} = 15\text{ V}$ $T_C = 125\text{ }^\circ\text{C}$	-	49 36 130	-	ns ns ns

1. Limits guaranteed by design

**Table 7. Switching energy (inductive load) <sup>(1)</sup>**

Symbol	Parameter	Test conditions	Min	Typ.	Max	Unit
$E_{on}^{(2)}$ $E_{off}^{(3)}$ $E_{ts}$	Turn-on switching losses Turn-off switching losses Total switching losses	$V_{CC} = 400\text{ V}$ , $I_C = 5\text{ A}$ $R_G = 10\ \Omega$ , $V_{GE} = 15\text{ V}$	-	TBD 60 TBD	-	$\mu$ J $\mu$ J $\mu$ J
$E_{on}^{(2)}$ $E_{off}^{(3)}$ $E_{ts}$	Turn-on switching losses Turn-off switching losses Total switching losses	$V_{CC} = 400\text{ V}$ , $I_C = 5\text{ A}$ $R_G = 10\ \Omega$ , $V_{GE} = 15\text{ V}$ $T_C = 125\text{ }^\circ\text{C}$	-	TBD 150 TBD	-	$\mu$ J $\mu$ J $\mu$ J

1. Limits guaranteed by design
2. IGBT and diode are at the same temperature
3. Turn-off losses include also the tail of the collector current

**Table 8. Collector-emitter diode**

Symbol	Parameter	Test conditions	Min	Typ.	Max	Unit
$V_F$	Forward on-voltage	$I_F = 3\text{ A}$ $I_F = 3\text{ A}$ , $T_C = 125\text{ }^\circ\text{C}$	-	1.8 1.3	-	V V
$t_{rr}^{(1)}$ $Q_{rr}^{(1)}$ $I_{rm}^{(1)}$	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_F = 3\text{ A}$ , $V_R = 400\text{ V}$ , $di/dt = 100\text{ A}/\mu\text{s}$	-	31 37 2.2	-	ns nC A
$t_{rr}^{(1)}$ $Q_{rr}^{(1)}$ $I_{rm}^{(1)}$	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_F = 3\text{ A}$ , $V_R = 400\text{ V}$ , $T_C = 125\text{ }^\circ\text{C}$ , $di/dt = 100\text{ A}/\mu\text{s}$	-	50 85 2.8	-	ns nC A

1. Limits guaranteed by design

Figure 2. IGBT thermal impedance

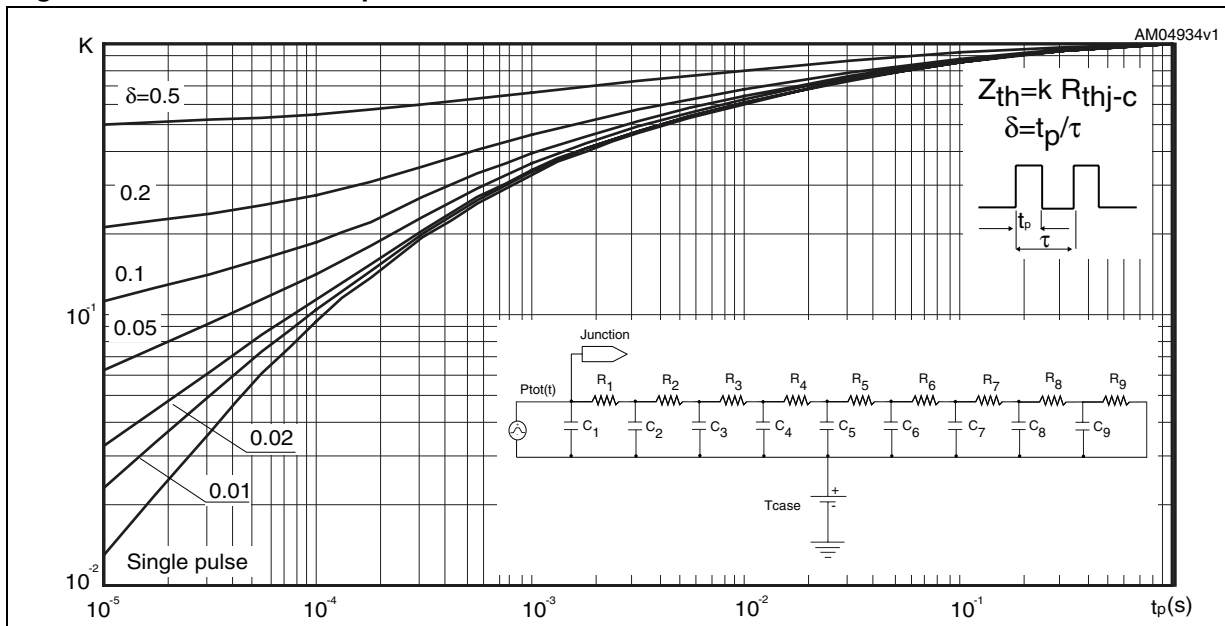


Table 9. IGBT RC-Cauer thermal network

Symbol	Value	Unit	Symbol	Value	Unit
\$R_1\$	0.344	\$^\circ\text{C}/\text{W}\$	\$C_1\$	0.4E-3	\$\text{W}^*\text{s}/^\circ\text{C}\$
\$R_2\$	0.0686	\$^\circ\text{C}/\text{W}\$	\$C_2\$	0.162E-4	\$\text{W}^*\text{s}/^\circ\text{C}\$
\$R_3\$	0.0958	\$^\circ\text{C}/\text{W}\$	\$C_3\$	0.684E-3	\$\text{W}^*\text{s}/^\circ\text{C}\$
\$R_4\$	0.177	\$^\circ\text{C}/\text{W}\$	\$C_4\$	0.923E-4	\$\text{W}^*\text{s}/^\circ\text{C}\$
\$R_5\$	0.250	\$^\circ\text{C}/\text{W}\$	\$C_5\$	0.3E-2	\$\text{W}^*\text{s}/^\circ\text{C}\$
\$R_6\$	0.245	\$^\circ\text{C}/\text{W}\$	\$C_6\$	0.9E-2	\$\text{W}^*\text{s}/^\circ\text{C}\$
\$R_7\$	0.152	\$^\circ\text{C}/\text{W}\$	\$C_7\$	0.678E-3	\$\text{W}^*\text{s}/^\circ\text{C}\$
\$R_8\$	0.135	\$^\circ\text{C}/\text{W}\$	\$C_8\$	0.807E-3	\$\text{W}^*\text{s}/^\circ\text{C}\$
\$R_9\$	0.530	\$^\circ\text{C}/\text{W}\$	\$C_9\$	0.248	\$\text{W}^*\text{s}/^\circ\text{C}\$

Figure 3. Diode thermal impedance

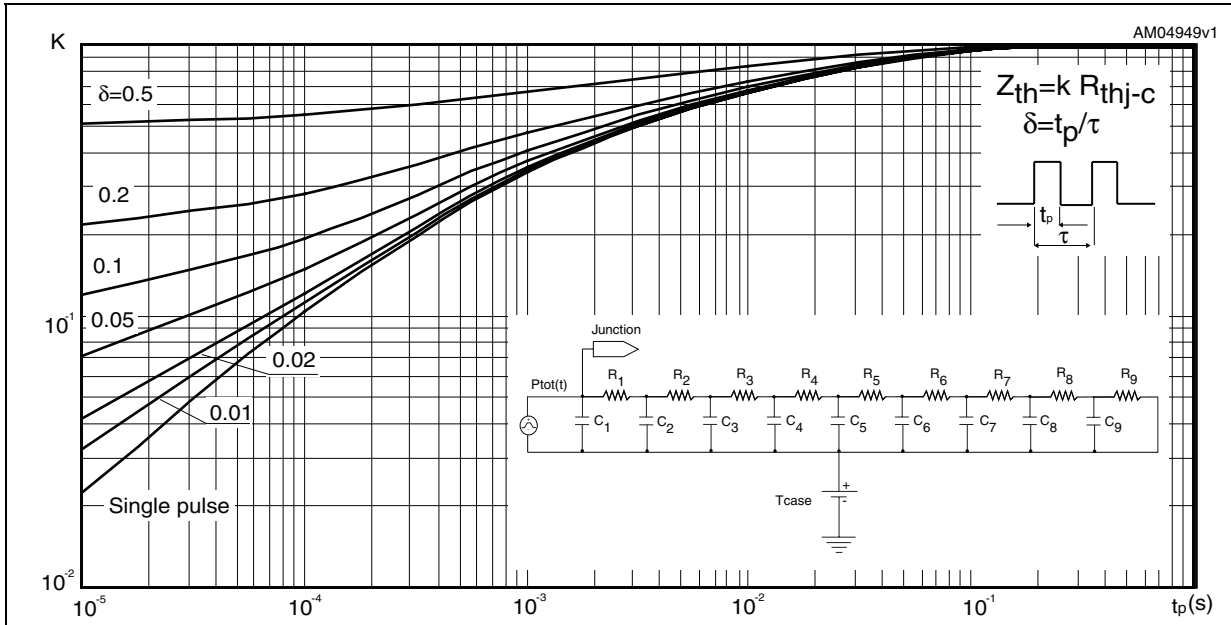
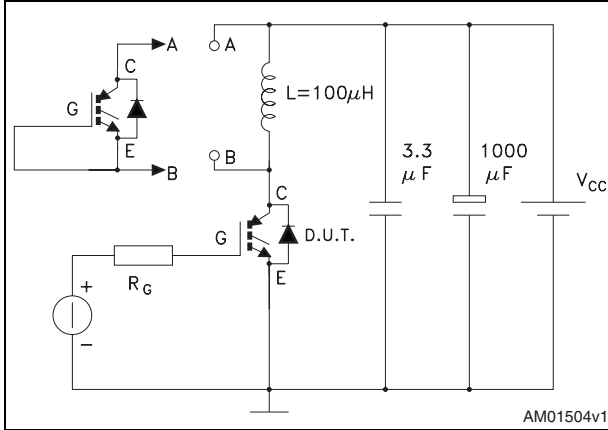


Table 10. Diode RC-Cauer thermal network

Symbol	Value	Unit	Symbol	Value	Unit
$R_1$	0.478	$^{\circ}C/W$	$C_1$	0.8E-4	$W^*s/^{\circ}C$
$R_2$	0.542	$^{\circ}C/W$	$C_2$	1E-4	$W^*s/^{\circ}C$
$R_3$	0.600	$^{\circ}C/W$	$C_3$	2E-4	$W^*s/^{\circ}C$
$R_4$	0.277	$^{\circ}C/W$	$C_4$	0.5E-5	$W^*s/^{\circ}C$
$R_5$	0.844	$^{\circ}C/W$	$C_5$	0.145E-2	$W^*s/^{\circ}C$
$R_6$	0.313	$^{\circ}C/W$	$C_6$	0.499E-4	$W^*s/^{\circ}C$
$R_7$	0.108	$^{\circ}C/W$	$C_7$	0.727E-3	$W^*s/^{\circ}C$
$R_8$	0.891	$^{\circ}C/W$	$C_8$	0.393E-4	$W^*s/^{\circ}C$
$R_9$	1.73	$^{\circ}C/W$	$C_9$	0.0176	$W^*s/^{\circ}C$

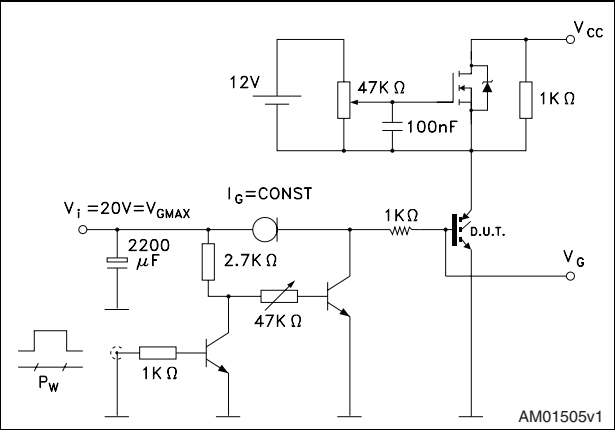
### 3 Test circuits

**Figure 4. Test circuit for inductive load switching**



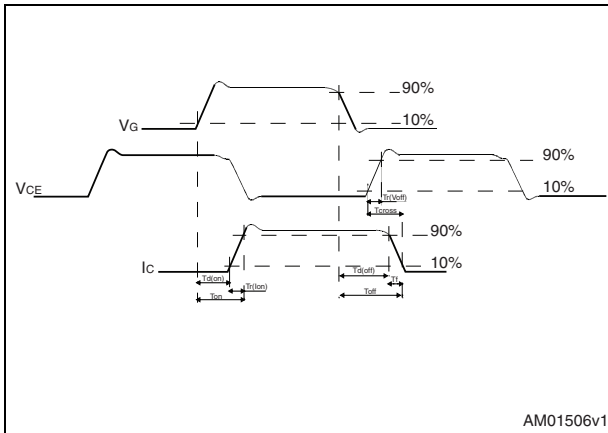
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**Figure 5. Gate charge test circuit**



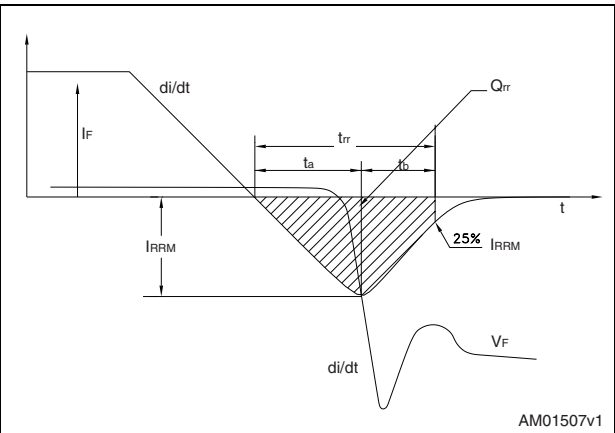
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**Figure 6. Switching waveforms**



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**Figure 7. Diode recovery times waveform**



AM01507v1

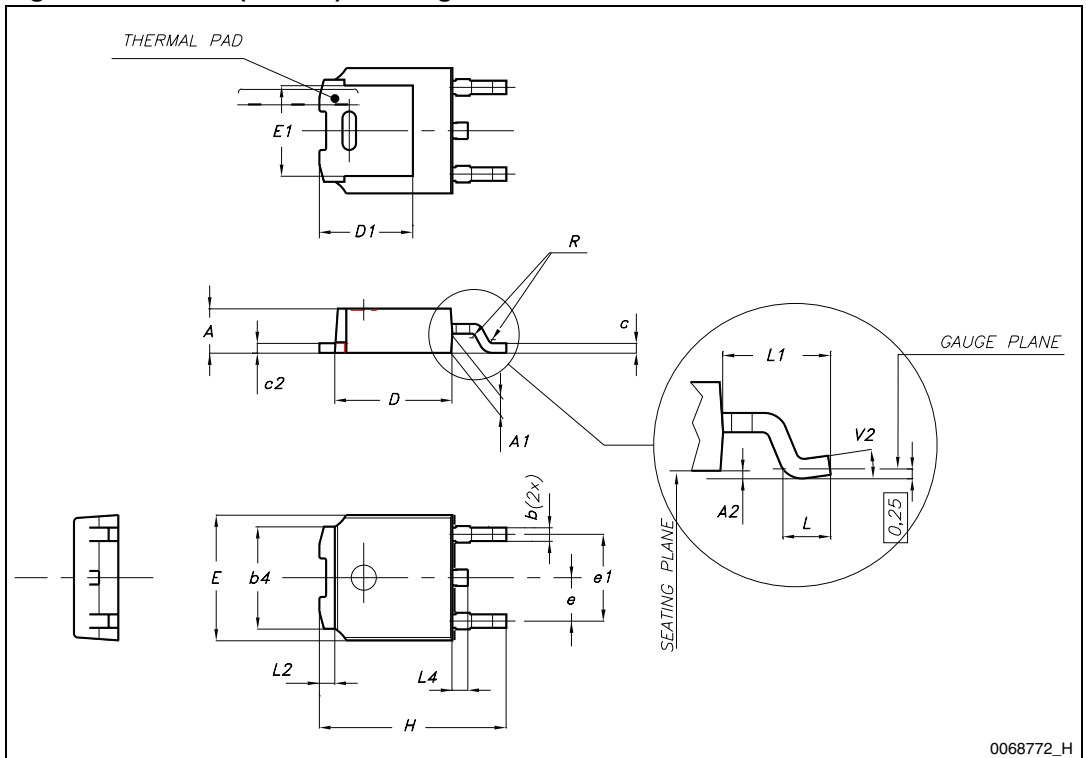
## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK<sup>®</sup> packages, depending on their level of environmental compliance. ECOPACK<sup>®</sup> specifications, grade definitions and product status are available at: [www.st.com](http://www.st.com). ECOPACK is an ST trademark.

**Table 11. DPAK (TO-252) mechanical data**

Dim.	mm		
	Min.	Typ.	Max.
A	2.20		2.40
A1	0.90		1.10
A2	0.03		0.23
b	0.64		0.90
b4	5.20		5.40
c	0.45		0.60
c2	0.48		0.60
D	6.00		6.20
D1		5.10	
E	6.40		6.60
E1		4.70	
e		2.28	
e1	4.40		4.60
H	9.35		10.10
L	1		1.50
L1		2.80	
L2		0.80	
L4	0.60		1
R		0.20	
V2	0°		8°

Figure 8. DPAK (TO-252) drawing

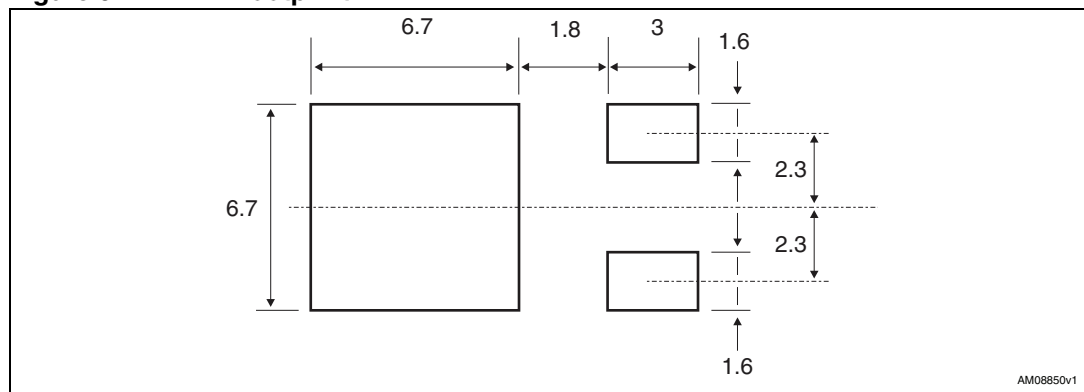


## 5 Packaging mechanical data

Table 12. DPAK (TO-252) tape and reel mechanical data

Tape			Reel		
Dim.	mm		Dim.	mm	
	Min.	Max.		Min.	Max.
A0	6.8	7	A		330
B0	10.4	10.6	B	1.5	
B1		12.1	C	12.8	13.2
D	1.5	1.6	D	20.2	
D1	1.5		G	16.4	18.4
E	1.65	1.85	N	50	
F	7.4	7.6	T		22.4
K0	2.55	2.75			
P0	3.9	4.1	Base qty.	2500	
P1	7.9	8.1	Bulk qty.	2500	
P2	1.9	2.1			
R	40				
T	0.25	0.35			
W	15.7	16.3			

Figure 9. DPAK footprint (a)



a. All dimensions are in millimeters

Figure 10. Tape for DPAK (TO-252)

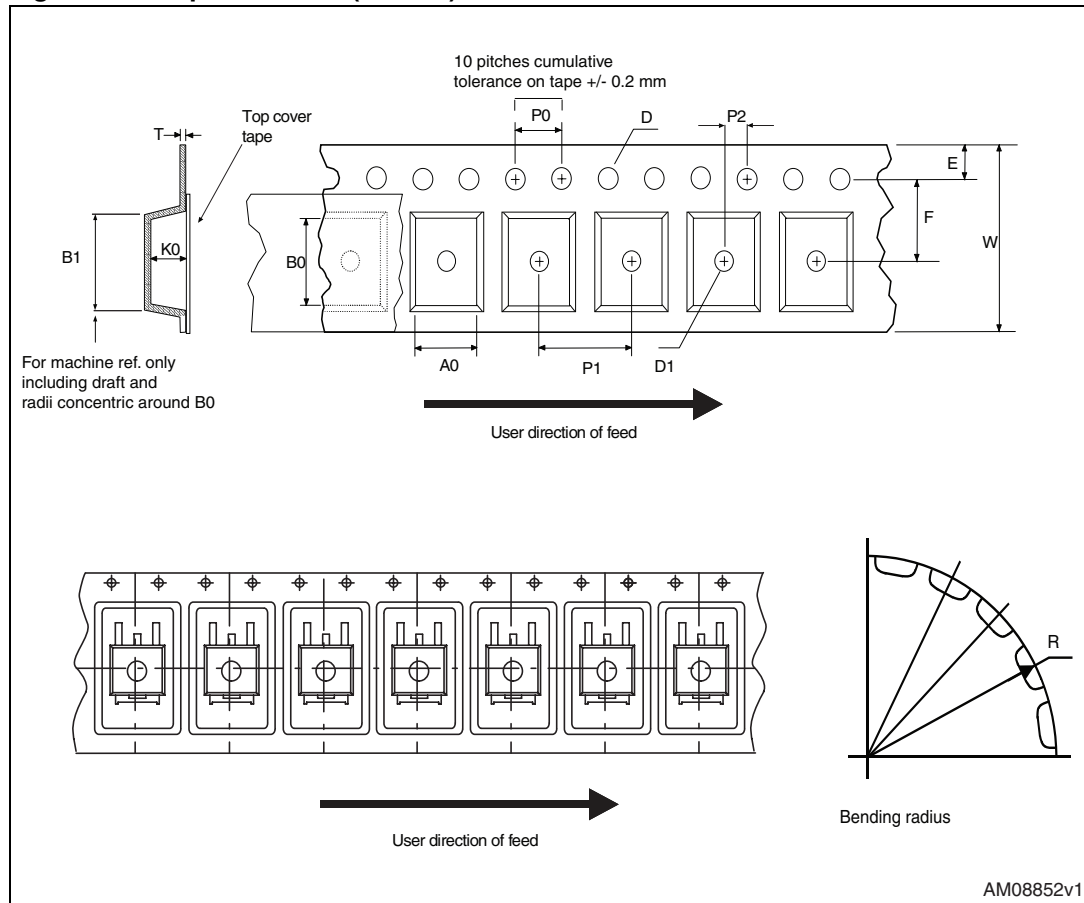
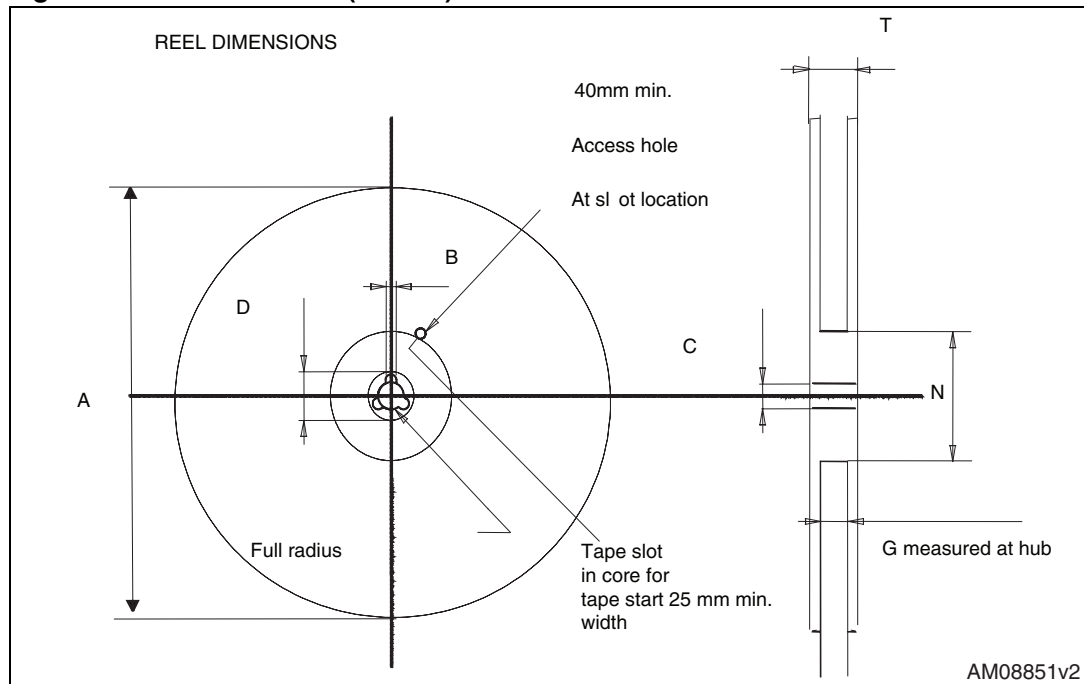


Figure 11. Reel for DPAK (TO-252)



## 6 Revision history

**Table 13. Document revision history**

Date	Revision	Changes
28-Feb-2012	1	First release

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